Abstracts

A Generalized Method for Evaluating the Metallization Thickness Effects on Microstrip Structures

T.-S. Horng. "A Generalized Method for Evaluating the Metallization Thickness Effects on Microstrip Structures." 1994 MTT-S International Microwave Symposium Digest 94.2 (1994 Vol. II [MWSYM]): 1009-1012.

This paper presents a generalized method for analyzing microstrip structures with finite metallization thickness. A spectral-domain approach that adopts proper current expansion functions is employed to find the three-dimensional current distribution in a finitely thick microstrip. Comparison of computed dispersion curves with available published data for microstrip lines of finite thickness illustrates the accuracy of this method. The influence of metallization thickness on discontinuities like patches and open-ends is also demonstrated.

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